


<b>Search Notes</b>  	<b>Application/Control No.</b>  10711593	<b>Applicant(s)/Patent Under Reexamination</b>  FAIRCHILD, MARK D.
	<b>Examiner</b>  BENJAMIN P LEE	<b>Art Unit</b>  3641

SEARCHED			
Class	Subclass	Date	Examiner
244	199.2	1/17/2008	LEE
244	99.12	1/17/2008	LEE
244	198	1/17/2008	LEE
244	199.1	1/17/2008	LEE
244	199.3	1/17/2008	LEE
244	218	1/17/2008	LEE
244	219	1/17/2008	LEE
244	90r	1/17/2008	LEE
244	90a	1/17/2008	LEE
244	45r	1/17/2008	LEE
244	199.4	1/17/2008	LEE

SEARCH NOTES		
Search Notes	Date	Examiner
updated search	1/17/2008	LEE

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner